

#### SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 & ANSI/NCSL Z540-1-1994

#### TRI-STATE INSTRUMENT SERVICE, INC. 8411 Clinton Park Drive Ft. Wayne, IN 46825 Lynn A. Stroble Phone: 260 456 4545

#### CALIBRATION

Valid To: June 30, 2024

Certificate Number: 1622.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following dimensional calibrations<sup>1, 6</sup>:

#### I. Dimensional

| Parameter/Equipment  | Range                            | CMC <sup>2, 4</sup> (±)              | Comments                                 |
|--|----------------------------------|--------------------------------------|--|
| Bench Micrometers <sup>3</sup>                             | Up to 2 in                       | 20 µin                               | Gage blocks                              |
| Bore Gages – Internal<br>Diameter (Hole Test – 3<br>Point) | Up to 0.1 in travel              | 40 μin                               | Micrometer heads & custom fixture        |
|  | (0.0625 to 8) in                 | (65 + 1.5D) µin                      | Ring gages                               |
| Dial Indicator –<br>Calibrator & Micrometer<br>Heads       | Up to 1 in<br>Up to 2 in         | 5.4 μin<br>(10 + 1.0 <i>L</i> ) μin  | Heidenhain CT-2501<br>Heidenhain CT-6001 |
| Calipers <sup>3</sup>                                      | (0.01 to 12) in<br>(12 to 48) in | 330 μin<br>(330 + 6.0 <i>L</i> ) μin | Gage blocks<br>Mic standards             |
| Chamfer Check <sup>3</sup>                                 | (0.02 to 2) in                   | 500 µin                              | Special ring gages                       |

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| Parameter/Equipment                               | Range   | CMC <sup>2, 4</sup> (±)                                | Comments   |
|---|---|--|--|
| Height Gages –                                    | Up to 24 in<br>(24 to 40) in                              | (130 + 2.5 <i>L</i> ) μin<br>(170 + 2.5 <i>L</i> ) μin | Webber bar & high-<br>resolution height gage       |
| High Resolution                                   | 24 in w/ $\leq$ 0.001 in resolution                       | (25 + 2.0 <i>L</i> ) μin                               |  |
| LH-600 Type                                       | Up to 39 in < 0.0001 in resolution                        | (14 + 2.0 <i>L</i> ) μin                               |  |
| Height Masters,<br>Digi-Checks,<br>Hite-Indicator | Up to 24 in   | (14 + 2.0 <i>L</i> ) μin                               | Webber bar & high-<br>resolution height gage       |
| Indicators <sup>3</sup> –                         |   |  |  |
| Dial & Digital                                    | < 0.01 in<br>(0.01 to 1) in<br>(1 to 2) in<br>(2 to 4) in | 5 μin<br>15 μin<br>24 μin<br>(40 + 17 <i>L</i> ) μin   | Heidenhain<br>Micrometer heads &<br>custom fixture |
| Test  | (0.001, 0.0005, 0.0001) in<br>(0.01, 0.005, 0.001) mm     | 20 μin<br>0.0005 mm                                    |  |
| Micrometers –                                     |   |  |  |
| Outside – Spindle<br>Only <sup>3</sup>            | (Up to 12) in<br>(12 to 40) in                            | (33 + 2.0 <i>L</i> ) μin<br>(75 + 2.0 <i>L</i> ) μin   | Gage blocks &<br>micrometer standards              |
| Depth <sup>3</sup>                                | Up to 12 in   | (150 + 8.0 <i>L</i> ) µin                              | Gage blocks  |
| Inside  | (0.25 to 24) in   | (150 + 1.5 <i>L</i> ) μin                              | CMM or LH-600                                      |
| Thread  | Up to 2 in  | 75 µin   | Thread plugs                                       |
| V-Anvil   | (0.09 to 4) in  | 100 µin  | CMM & pin gages                                    |
| Calibration Masters –                             |   |  |  |
| Mikemaster  | Up to 3 in  | 15 µin   | THV  |
| Outside Diameter                                  | (0.5 to 12) in  | (20 + 3.2D) μin  | ULM  |
| Kalmaster   | Up to 12 in   | (25 + 1.5 <i>L</i> ) μin                               | LH-600 & Webber bar                                |
| Depth Master                                      | Up to 12 in   | (25 + 1.5 <i>L</i> ) μin                               | LH-600 & Webber bar                                |

| Parameter/Equipment                | Range                          | CMC <sup>2, 4</sup> (±)                             | Comments                            |
|------------------------------------|--------------------------------|---|-------------------------------------|
| Levels                             | Up to 15 in length             | 100 µin/ft  | Special level checker               |
| Electronic Levels                  | Up to 100 arc sec.             | 1.3 arc sec.  |                                     |
| Standards –                        |                                |   |                                     |
| Micrometer                         | Up to 24 in<br>(> 24 to 40) in | (15 + 5 <i>L</i> ) μin<br>(110 + 1.5 <i>L</i> ) μin | ULM<br>LH-600 & Webber bar          |
| Thread Micrometer                  | Up to 4 in                     | $(50 + 2L) \mu in$                                  | ULM                                 |
| Squares                            | Up to 30 in                    | (120 + 15 <i>L</i> ) μin                            | СММ                                 |
| Sine Bars (Up to 10 in) –<br>Angle | Up to 45 °                     | 0.000 85 °  | СММ                                 |
| Parallelism                        | 1                              | 25 µin  |                                     |
| Flatness                           |                                | 25 µin  |                                     |
| Surface Finish                     | Up to 400 Ra<br>µin patch      | 2.3 μin Ra  | Reference master                    |
| Surface Finish Testers –           |                                |   |                                     |
| Ra Parameter                       | Up to 400 Ra                   | 2.5 µin Ra  | Reference master                    |
| Linearity                          | Up to 400 Ra                   | 2.5 μin Ra  |                                     |
| Repeatability                      | Actual                         | 0.6 resolution                                      |                                     |
| Optical Comparators <sup>3</sup> – |                                |   |                                     |
| Magnification                      | Up to 100 X                    | 0.01 % magnification                                | Glass scales, length                |
| Linear Travel                      | Up to 12 in<br>(12 to 20) in   | 240 μin<br>320 μin                                  | standards, angle<br>blocks, squares |
| Squareness                         | X to Y Axis                    | 100 µin   |                                     |

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| Parameter/Equipment                              | Range                           | CMC <sup>2, 4</sup> (±)                            | Comments                                    |
|--|---------------------------------|--|---|
| Major Diameter –                                 |                                 |  |   |
| Pin Gages  | (0.011 to 1) in                 | 10 µin   | THV   |
| Reversible Wires                                 | Up to 1 in                      | 7 µin  | THV   |
| Plain Plugs                                      | Up to 2 in<br>(2 to 12) in      | (7 + 1 <i>D</i> ) μin<br>(7 + 1.5 <i>D</i> ) μin   | THV<br>ULM                                  |
| XX – Tolerance Plug                              | Up to 2 in                      | 5 µin  | THV   |
| Inside Diameter – Ring Gages                     | (0.04 to 4) in                  | (7 + 0.5 <i>D</i> ) μin                            | Diamet, P&W internal                        |
|  | (4 to 12) in                    | (7 + 1.5 <i>D</i> ) μin                            | ULM   |
| Rules –  |                                 |  |   |
| Steel  | Up to 48 in<br>(> 48 to 120) in | (120 + 4 <i>L</i> ) μin<br>(200 + 6 <i>L</i> ) μin | CMM & video system                          |
| Glass  | Up to 24 in                     | $(20 + 2L) \mu in$                                 |   |
| Thread Gages –                                   |                                 |  |   |
| Standard Work & Set Plugs –<br>Pitch Diameter    | Up to 6 in                      | (45 + 2 <i>D</i> ) μin                             | Custom bench<br>micrometer, thread<br>wires |
| Adjustable Ring Gages                            | (0.04 to 6) in                  | 150 µin  | Set plugs                                   |
| Adjustable & Solid Ring<br>Gage – Pitch Diameter | (0.5 to 6) in                   | 91 µin   | 2 Point P.D. ULM                            |
| Surface Plates <sup>3</sup> –                    |                                 |  |   |
| Flatness Grade AA, A, & B                        | (10 to 108) in Diagonal         | (29 + 1 <i>D</i> ) μin                             | Electronic level system                     |
| Repeatability                                    | Up to 0.002 in                  | 20 µin   | Repeat-o-meter                              |
| Spheres & Precision Balls                        | Up to 2 in                      | (5 + 1 <i>D</i> ) μin                              | THV   |

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| Parameter/Equipment                          | Range               | CMC <sup>2, 4</sup> (±) | Comments  |
|--|---------------------|-------------------------|---|
| Optical Parallels –                          |                     |                         |   |
| Parallelism Length –<br>Thickness            | Up to 1 in Thick    | 5 µin                   | Heidenhain  |
| Flatness – Parallels                         | Up to 4 in Diameter | 5 µin                   | Three optical flat method                                 |
| Optical Flats                                | Up to 4 in Diameter | 5 µin                   | Comparison to master                                      |
| Length – Between Two<br>Planes (Step Length) | (0.01 to 1.5) in    | 32 µin                  | Heidenhain  |
| Plain Tapered Plugs –<br>External Diameter   |                     |                         |   |
| 0.75 TPF                                     | (0.01 to 4) in      | 49 µin                  | Custom bench micrometer<br>& rolls                        |
| All Tapers                                   | (0.01 to 8) in      | 25 µin                  | Standard measuring<br>machine, gage block &<br>rolls      |
| Plain Tapered Rings –<br>Internal Diameter   |                     |                         |   |
| 0.75 TPF                                     | (0.04 to 4) in      | 71 µin                  | СММ   |
| All Tapers                                   | (0.04 to 8) in      | 81 µin                  |   |
| External Tapered Thread<br>Plug              |                     |                         |   |
| Pitch Diameter                               | (0.047 to 4) in     | 72 µin                  | Custom bench micrometer                                   |
| Major Diameter                               | (0.1 to 4) in       | 44 µin                  | Custom bench micrometer                                   |
| Internal Tapered Thread Plug                 |                     |                         |   |
| Pitch Diameter                               | (0.06 to 4) in      | 91 µin                  | Tapered master plug &<br>Heidenhain (stand-off<br>method) |

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| Parameter/Equipment   | Range                 | CMC <sup>2, 4</sup> (±)   | Comments  |
|-----------------------|-----------------------|---------------------------|---|
| Thread Wires          |                       |                           |   |
| Inch                  | (4 to 120) TPI        | 6.5 µin                   | Master wire & THV   |
| Metric                | (0.2 to 10) Pitch     | 6.5 µin                   |   |
| Gage Block            | Up to 4 in            | (3.8 + 0.5 <i>L</i> ) μin | CT-6001 Heidenhain w/<br>master gage blocks<br>single point measurement |
| Geometry <sup>5</sup> |                       |                           | Various measuring   |
| Length                |                       |                           | devices including but not limited to:                                   |
| 1D                    | Up to 28 in           | $(30 + 4L) \mu in$        | Video, CMM, height<br>gage, gage blocks, ULM,                           |
| 2D                    | 20 in x 38 in         | $(40 + 4L) \mu in$        | THV, optical comparators, masters,                                      |
| 3D                    | 20 in x 28 in x 16 in | $(40 + 4L) \mu in$        | etc.  |
| Angles                | Up to 360 $^{\circ}$  | 15 sec                    |   |
| Diameter/Radius       | Up to 12 in           | $(40 + 4L) \mu in$        |   |
| Straightness          | Up to 50 in           | 50 µin per 12 in          |   |
| Radius Gages          | Up to 2 in            | 150 μin                   | Optical/video comparator  |

<sup>1</sup> This laboratory offers commercial and field calibration services.

<sup>2</sup> Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of k = 2. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

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- <sup>3</sup> Field calibration service is available for this calibration. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.
- <sup>4</sup> In the statement of CMC, L is the nominal length in inches; D is the nominal diameter in inches.
- <sup>5</sup> For Geometry measurements the best CMC may vary depending upon the type of measuring equipment utilized.
- <sup>6</sup> This scope meets A2LA's *P112 Flexible Scope Policy*.

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# **Accredited Laboratory**

A2LA has accredited

## **TRI-STATE INSTRUMENT SERVICE, INC.**

Ft. Wayne, IN

for technical competence in the field of

### Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 General requirements for the competence of testing and calibration laboratories. This laboratory also meets the requirements of ANSI/NCSL Z540-1-1994 and – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 25<sup>th</sup> of August 2022.

Vice President, Accreditation Services For the Accreditation Council Certificate Number 1622.01 Valid to June 30<sup>th</sup> 2024